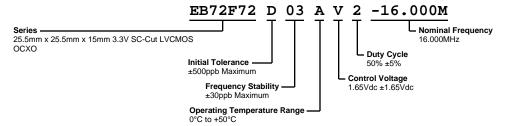
# EB72F72D03AV2-16.000M





ELECTRICAL SPECIFICATIONS		
Nominal Frequency	16.000MHz	
Initial Tolerance	±500ppb Maximum (Measured at nominal Vdd and Vc)	
Frequency Stability	±30ppb Maximum	
Frequency Stability vs. Input Voltage	±20ppb Maximum (Vdd ±5%)	
Frequency Stability vs. Load	±20ppb Maximum (Vload ±5%)	
Frequency Stability vs. Aging (10 Years)	±500ppb Maximum (after 72 hours of operation)	
Frequency Stability vs. Aging (1 Day)	±2.0ppb Maximum (after 72 hours of operation)	
Frequency Stability vs. Aging (1 Year)	±100ppb Maximum (after 72 hours of operation)	
Operating Temperature Range	0°C to +50°C	
Supply Voltage	3.3Vdc ±5%	
Warm Up Time	3 Minutes Maximum (to ±50ppb of final frequency at 1 hour at 25°C)	
Power Consumption	1.2Watts Maximum at Steady State at 25°C, 3.6Watts Maximum during Warm Up	
Output Voltage Logic High (Voh)	2.6Vdc Minimum (IOH=-4mA)	
Output Voltage Logic Low (Vol)	0.4Vdc Maximum (IOL=+4mA)	
Rise/Fall Time	6nSec Maximum (Measured at 20% to 80% of waveform)	
Duty Cycle	50% ±5% (Measured at 50% of waveform)	
Load Drive Capability	15pF Maximum	
Output Logic Type	CMOS	
Control Voltage	1.65Vdc ±1.65Vdc	
Control Voltage Range	0.0Vdc to Vdd	
Frequency Deviation	±0.5ppm Minimum (Referenced to Fo at Vc=1.65Vdc; Vcc=3.3Vdc)	
Linearity	±10% Maximum	
Reference Voltage Output	2.8Vdc ±0.2Vdc (Pin 4)	
Transfer Function	Positive Transfer Characteristic	
Crystal Cut	SC-Cut	
Input Impedance	10kOhms Typical	
Phase Noise	-90dBc/Hz at 1Hz Offset, -100dBc/Hz at 10Hz Offset, -130dBc/Hz at 100Hz Offset, -145dBc/Hz at 1kHz Offset, -150dBc/Hz at 10kHz Offset (Typical Values)	
Storage Temperature Range	-55°C to +125°C	

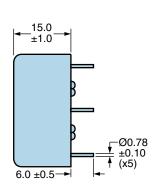
ENVIRONMENTAL & MECHANICAL SPECIFICATIONS		
Gross Leak Test	MIL-STD-883, Method 1014, Condition C	
Lead Integrity	MIL-STD-883, Method 2004	
Mechanical Shock	MIL-STD-202, Method 213 Condition C	
Resistance to Soldering Heat	MIL-STD-202, Method 210	
Resistance to Solvents	MIL-STD-202, Method 215	
Solderability	MIL-STD-883, Method 2003	
Temperature Cycling	MIL-STD-883, Method 1010	
Vibration	MIL-STD-883, Method 2007 Condition A	

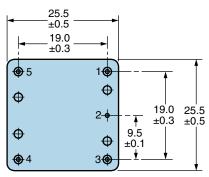
# EB72F72D03AV2-16.000M



### **MECHANICAL DIMENSIONS (all dimensions in millimeters)**



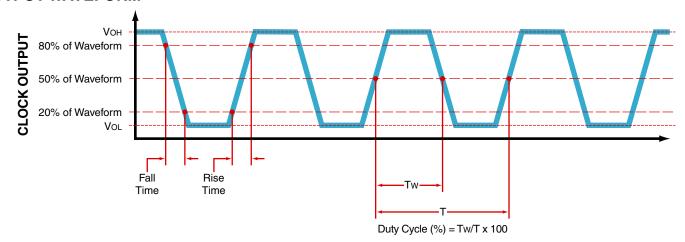




PIN	CONNECTION
1	Output
2	Case/Ground
3	Voltage Control
4	Reference Voltage Output
5	Supply Voltage

LINE	MARKING
1	ECLIPTEK
2	16.000M
3	XXYZZ XX=Ecliptek Manufacturing Code Y=Last Digit of the Year ZZ=Week of the Year

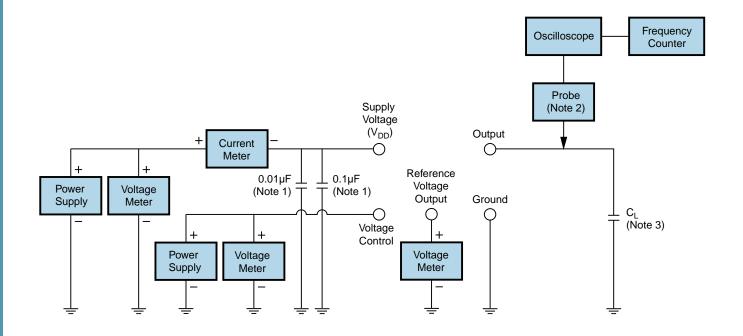
#### **OUTPUT WAVEFORM**



## EB72F72D03AV2-16.000M



### **Test Circuit for Voltage Control Option**



- Note 1: An external  $0.1\mu F$  low frequency tantalum bypass capacitor in parallel with a  $0.01\mu F$  high frequency ceramic bypass capacitor close to the package ground and  $V_{DD}$  pin is required.
- Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.
- Note 3: Capacitance value  $\dot{C}_L$  includes sum of all probe and fixture capacitance.